

A switchable white-beam neutron polariser

Aim: a polariser / analyser which

- does not alter the beam path
- accepts a wide bandwidth / divergence
- does not interfere with the sample environment (no stray fields)
- provides both spin states (without a flipper)

Approach: Fe/Si supermirror (SM) on Si (deposited by magnetron sputtering) [1, 2]

Advantages: magnetic hysteresis allows for switching [3]

no magnetic fields (besides guide field H_g) [4]
reflection and transmission mode possible

Disadvantages: q -range is limited by the stability of the coating
⇒ only $m = 3$ with 600 layers is reachable [a]

applications

- V-shaped polariser [5] for SANS I

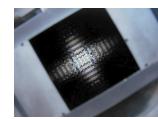
not yet switchable

$$P_T \approx 93\% @ 5 \text{ \AA}, 5 \text{ m}$$

$$\approx 95\% @ 5 \text{ \AA}, 15 \text{ m}$$

$$\approx 98\% @ 8 \text{ \AA}, 15 \text{ m}$$

$$B_g \approx 20 \text{ Oe}$$



- Switchable spin analyser for the 2 axes diffractometer TOPSI

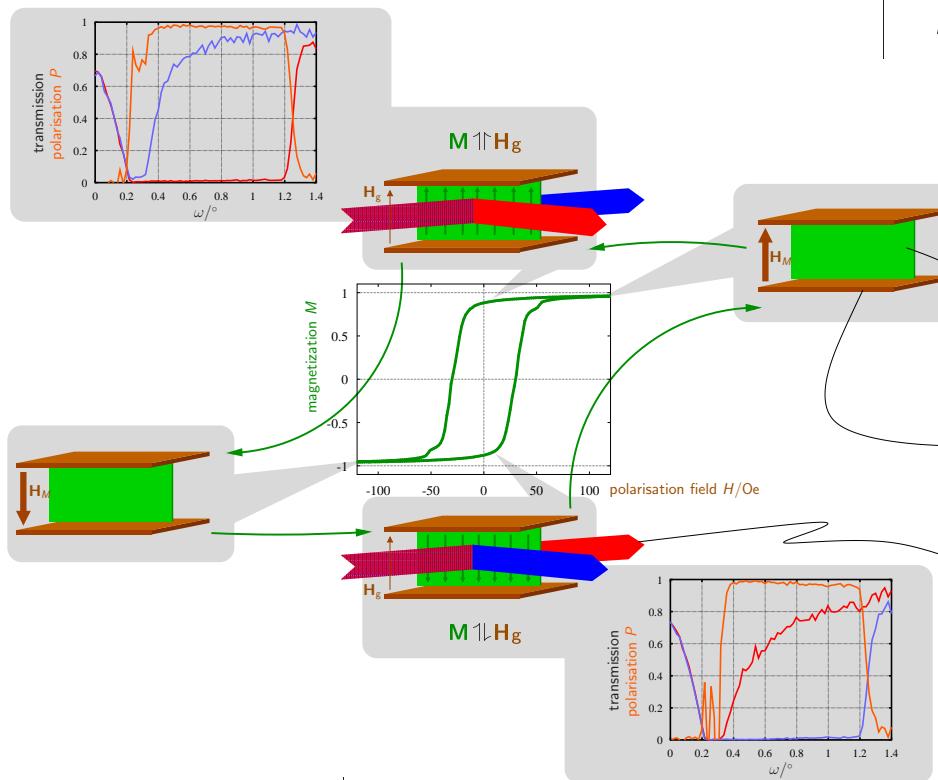
$m = 3$ Fe/Si SM on Si

$$P_T \approx 96\%, M \uparrow \uparrow H_g$$

$$P_T \approx 95\%, M \uparrow \downarrow H_g$$

$$B_g \approx 16 \text{ Oe}$$

$$B_M \approx 120 \text{ Oe}$$



Si wafer with supermirror
electro magnet

$$H_M \approx 120 \text{ Oe}$$

$$H_g < 40 \text{ Oe}$$

unpolarised / polarised neutrons

polarising efficiency

$$P = \frac{I_{\text{major}} - I_{\text{minor}}}{I_{\text{major}} + I_{\text{minor}}}$$

future projects

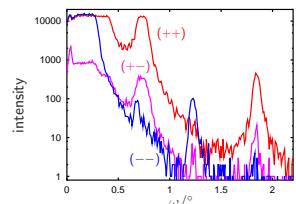
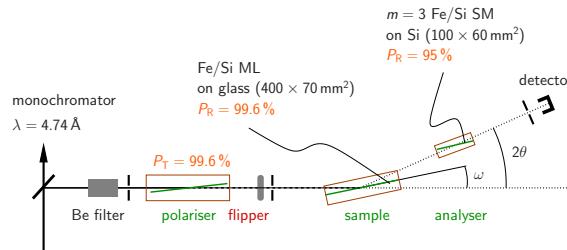
- analyser for the TOF reflectometer AMOR (switchable; usable in reflectometry and transmission mode simultaneously);
- compact polariser ($\approx 10 \text{ cm}$ [?]) for beamwidths $> 1 \text{ cm}$;
- improvement of the mechanical stability of the coating to allow for $m > 3$.

references

- [1] J. Stahn, D. Clemens: *Applied Physics A* **75**, 5153–5154 (2002)
- [2] J. Stahn, D. Clemens: *Proceedings of SPIE* **4785**, 126–133 (2002)
- [3] F. Semadeni, B. Roessli, P. Böni: *Physica B* **297**, 152–154 (2000)
- [4] C. Pappas et al.: *Physica B* **283**, 365–371 (2000)
- [5] T. Keller et al.: *N.I.M. Phys. Res. A* **451**, 474–479 (2000)
- [6] C. F. Majkrzak et al.: *Proceedings of SPIE* **1738**, 90–115 (1992)
- [a] m is a measure for the critical angle θ_{SM}^* relative to Ni: $\theta_{\text{SM}}^* := m \theta_{\text{Ni}}^*$

set-up for transmission and reflectivity measurements

Lay-out of the two axes spectrometer TOPSI @ SINQ



Reflectivity curves of a [Fe(80 Å)/Si(80 Å)]₁₀ multilayer: $I_{\perp} = 2.4\% I_{++} + 3.1\% I_{+-}$
(caused by the efficiencies of the analyser and of the spin-flipper).

acknowledgements

Thanks to J. Kohlbrecher and V. Asval for helping with the measurements and for supplying the data from SANS I. This project is embedded in the EU network TECHNI, it is financially supported by the BBW Switzerland (No. 99.0593). This work was performed at the Swiss Spallation Neutron Source (SINQ), Paul Scherrer Institute, Villigen, Switzerland, on the instruments TOPSI and SANS I.

contact

Jochen Stahn, Laboratorium für Neutronenstreuung WHGA / 142, CH-5231 Villigen PSI
email: jochen.stahn@psi.ch, tel: +41 (0)56 310 2518